

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/646,955	CHEN ET AL.	
	Examiner	Art Unit	
	David Q. Nguyen	2681	

SEARCHED			
Class	Subclass	Date	Examiner
370	329	10/10/05	DN
	340		
	229		
	230		
	230.1		
	282		
	288		
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380	441		
455	454	10/12/05	DN